

Search Notes

Application/Control No.

10/524,177

Examiner

Huy D. Nguyen

Applicant(s)/Patent under
Reexamination

VERMA ET AL.

Art Unit

2617

SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|-----------|----------|
| 455 | 410 | 4/4/2006 | HN |
| | 411 | | |
| | 435.1 | | |
| | 435.2 | | |
| | 432.1 | | |
| | 432.2 | | |
| | 433 | | |
| | 434 | | |
| | 436 | | |
| | 422.1 | | |
| Updated | search | 8/25/2006 | HN |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout. | 4/4/2006 | HN |
| East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout. | 8/25/2006 | HN |
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